



Docket No.: 63979-033

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Yoshihiko KANZAWA, et al.

Serial No.: 10/674,523

Filed: October 01, 2003

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Confirmation No: 5372

Group Art Unit: Not yet Assigned

Examiner: To be Assigned

For: METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT ELEMENT
CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR DEVICE (As
amended)

PRELIMINARY AMENDMENT

Mail Stop
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Prior to examination of the above-referenced application, please amend the application as
follows:

IN THE SPECIFICATION: